SN54LS373, SN54LS374, SN54S373, SN54S374, SN54S373, SN74LS374, SN74S373, SN74S374 SDLS165 OCTAL D-TYPE TRANSPARENT LATCHES AND EDGE-TRIGGERED FLIP-FLOPS

OCTOBER 1975-REVISED MARCH 1988

- Choice of 8 Latches or 8 D-Type Flip-Flops In a Single Package
- 3-State Bus-Driving Outputs
- · Full Parallel-Access for Loading
- Buffered Control Inputs
- Clock/Enable Input Has Hysteresis to Improve Noise Rejection ('S373 and 'S374)
- P-N-P Inputs Reduce D-C Loading on Data Lines ('S373 and 'S374)

'LS373, 'S373 FUNCTION TABLE

Γ	OUTPUT	ENABLE		OUTPUT	1
l	ENABLE	LATCH	D	OUTPUT	
Ţ	L	н	Н	Н	1
ĺ	L	Н.	L	L	l
-	Ŀ,	\ L	Х	α_0	١
١	Н	X	X	z	ı

'LS374, 'S374 FUNCTION TABLE

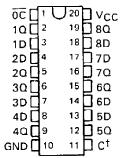
OUTPUT ENABLE	CLOCK	D	OUTPUT
L	†	Н	Н
L	↑	L	L
L	L	X	20
Н	x	Х	Ž

description

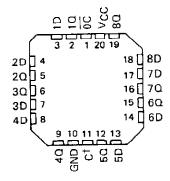
These 8-bit registers feature three-state outputs designed specifically for driving highly-capacitive or relatively low-impedance loads. The high-impedance third state and increased high-logic-level drive provide these registers with the capability of being connected directly to and driving the bus lines in a bus-organized system without need for interface or pull-up components. They are particularly attractive for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight latches of the 'LS373 and 'S373 are transparent D-type latches meaning that while the enable (C) is high the Q outputs will follow the data (D) inputs. When the enable is taken low the output will be latched at the level of the data that was set up.

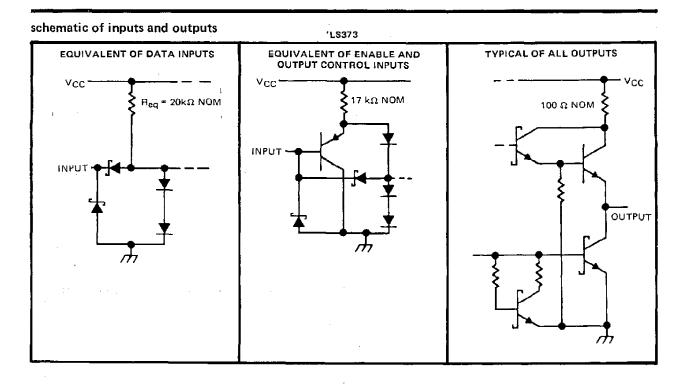
SN54LS373. SN54LS374. SN54S373. SN54S374...J OR W PACKAGE SN74LS373, SN74LS374, SN74S373. SN74S374...DW OR N PACKAGE (TOP VIEW)

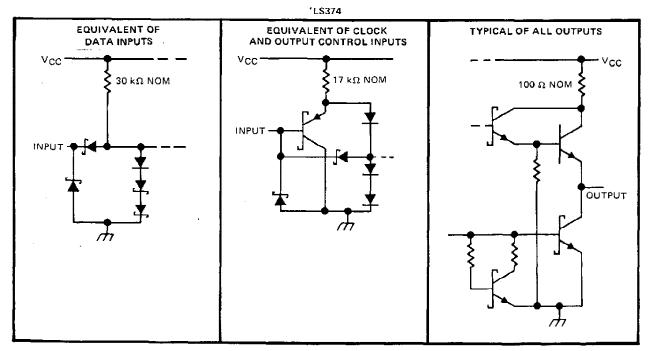


SN54LS373. SN54LS374, SN54S373. SN54S374 . . . FK PACKAGE (TOP VIEW)



¹C for 'LS373 and 'S373; CLK for 'LS374 and 'S374.





SN54LS373, SN54LS374, SN74LS373, SN74LS374 OCTAL D-TYPE TRANSPARENT LATCHES AND EDGE-TRIGGERED FLIP-FLOPS

absolute maximum ratings	over operating fr	ee-air temperatu	re range (unless	otherwise noted)

Supply voltage, V _{CC} (see Note 1)						_							. 7V
Input voltage													7 V
Off-state output voltage									-				5.5 V
Operating free-air temperature range: SN54LS'		-				,				_	55°	C to	125°C
SN74LS'				-				-			(رc °C	to 70°C
Storage temperature range										_	65°	C to	5 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

				SN54LS	<u>}'</u>		3,	UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	_ v
Vон	High-level output voltage				5.5			5.5	٧
юн	High-level output current				- 1			- 2.6	mA
10 L	Low-level output current		_		12			24	mA
tw	Pulse duration	CLK high	15			15			ns
		CLK low	15			15			[""
	Data setup time	'L\$373	5		***	5			
t _{su}	Data setup time	'L\$374	20	1		201			ns
•.	Data hold time	'L\$373	20	ļ		20 :			<u> </u>
t _h	Data noid time	'LS374 †	5	1		01			ns
TA	Operating free-air temperature	- ··· ·	- 55		125	0		70	°c

[†]The t_h specification applies only for data frequency below 10 MHz. Designs above 10 MHz should use a minimum of 5 ns. (Commercial only)

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIO	t	1	SN54LS	; *		SN74LS	i'	
	· Anameten	TEST CONDITIO	M2 1	MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
v_{IH}	High-level input voltage			2			2			V
VIL	Low-level input voltage					0.7			0.8	V
VIK	Input clamp voltage	V _{CC} = MIN, I _I = -18 mA				-1.5			1.5	V
νон	High-level output voltage	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = V _{IL} max, I _{OH} = MAX		2.4	3.4		2,4	3.1		V
Vol	Low-level putput voltage	V _{CC} = MIN, V _{IH} = 2 V,	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	
• UL	Eowalesel purbat sollage	V _f L = V _{fL} max	IOL = 24 mA			-		0.35	0.5	٧
10=0	Off-state output current,	V _{CC} = MAX, V _{IH} = 2 V,	- 							<u> </u>
IOZH	high-level voltage applied	V _O = 2.7 V				20			20	μΑ
losi	Off-state output current,	V _{CC} = MAX, V _{IH} = 2 V,								
JOZL	low-level voltage applied	Vo ≈ 0.4 V				-20			-20	μΑ
t ₁	Input current at maximum input voltage	V _{CC} = MAX, V _I = 7 V				0,1			0,1	mA
¹ 1H	High-level input current	V _{CC} = MAX, V ₁ = 2.7 V				20			20	μΑ
Iμ	Low-level input current	V _{CC} = MAX, V _I = 0.4 V				-0.4			-0.4	mA
^I OS	Short-circuit output current§	V _{CC} = MAX		-30		-130	-30		-130	mA
lac	Supply current	V _{CC} = MAX,	'LS373		24	40		24	40	
, GC	adplia conent	Output control at 4,5 V	'LS374		27	40		27	40	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$. § Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

SN54LS373, SN54LS374, SN74LS373, SN74LS374 OCTAL D-TYPE TRANSPARENT LATCHES AND EDGE-TRIGGERED FLIP-FLOPS

switching characteristics, VCC = 5 V, TA = 25°C

	FROM	TO			'LS373				UNIT	
PARAMETER	(INPUT)	(OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	ONIT
fmax							35	50		MHz
tPLH			1		12	18				ns
†PHL	Data	Any Q	0.70		12	18				113
^L PLH	Clock or		$C_L = 45 \text{ pF}, R_L = 667 \Omega$		20	30		15	28	ns
tPHL	enable	Any Q	See Notes 2 and 3		18	30		19	28	115
^t PZH	Output				15	28		20	26	ns
tPZL	Control	Any Q			25	36		21	28	113
t _{PHZ}	Output Control	Any Q	$C_{L} = 5 \text{ pF}, R_{L} = 667 \Omega$		15	25		15	28	ns
tpLZ	Output	Any Q	See Note 3		12	20		12	20	пs

NOTES: 2. Maximum clock frequency is tested with all outputs loaded.

3. Load circuits and voltage waveforms are shown in Section 1.

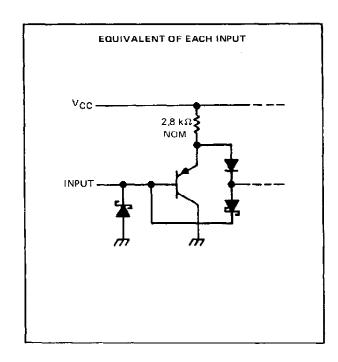
f_{max} ≡ maximum clock frequency

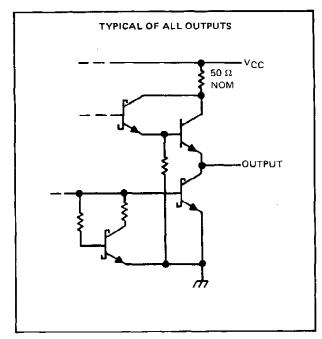
tpLH = propagation delay time, low-to-high-level output tpHL = propagation delay time, high-to-low-level output

tpZH = output enable time to high level
tpZL = output enable time to low level
tpHZ = output disable time from high level
tpLZ = output disable time from low level

SN54S373, SN54S374, SN74S373, SN74S374 OCTAL D-TYPE TRANSPARENT LATCHES AND EDGE-TRIGGERED FLIP-FLOPS

schematic of inputs and outputs





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)														. 7 V
Input voltage							,							5.5 V
Off-state output voltage					-									5.5 V
Operating free-air temperature range:														
	SN74S													
Storage temperature range				-		٠			٠		-	65°	C to	150°C

NOTE 1: Voltage values are with respect to network ground terminal,

recommended operating conditions

			SN54S'			SN745'		
	_	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, VCC		4.5	5	5.5	4.75	5	5.25	V
High-level output voltage, VOH				5.5			5.5	V
High-level output current, IOH				-2			6.5	mA
Width of clock/enable pulse, tw	High	6			6_			
	Low	7.3			7.3			ns
Data setup time, t _{su}	'S373	01			O.		-	
Cata setup time, isu	′5374	5↑			5↑			ns
Data hold time, th	' \$373	10↓			10↓			
Data noid (line, th	'5374	2†			2↑			ns
Operating free-air temperature, TA		~55		125	0		70	^c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARA	AMETER		TEST CO	ONDITIONS [†]		MIN	TYP	MAX	UNIT
V _{IH}						2			V
VIL								0.8	٧
VIK		V _{CC} = MIN,	I ₁ = -18 mA					- 1.2	V
V0	SN545'	V00 - MIN	V 2 V	V _{IL} = 0.8 V,	(a = MAY	2.4	3.4		
Vон	SN74S'	ACC = IAIIIA'	VIH = 2 V,	ν _{IL} = 0.6 ν,	10H = WAA	2.4	3.1		·
VOL	Ī	V _{CC} = MIN,	V _{IH} = 2 V.	$V_{IL} = 0.8 V_{c}$	I _{OL} = 20 mA			0.5	V
lozh		V _{CC} = MAX,	V _{IH} = 2 V,	Vo = 2.4 V				50	μA
lozL	_	VCC = MAX,	$V_{IH} = 2 V.$	V _O = 0.5 V				- 50	μΑ
11		V _{CC} = MAX,	V ₁ = 5.5 V	· · · · · · · · · · · · · · · · · · ·				1	mA
ΠH		V _{CC} = MAX,	V _I = 2.7 V					50	μA
IIL		VCC = MAX,	V _I = 0.5 V					-250	μΑ
los§		V _{CC} = MAX				-40		- 100	mA
					outputs high			160	
	ſ		'S373		outputs low			160	
1					outputs disabled			190	
Icc		$V_{CC} = MAX$			outputs high			110	mA
			'S374		outputs low			140	
	[;	3374		outputs disabled			160	
<u> </u>				CLK and OC a	at 4 V, D inputs at 0 V			180	

^{*}For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	FROM	то	TEST COMPLETIONS		' \$373			'S374		
FANAIVIETER	(INPUT)	(OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
fmax							75	100		MHz
^t PLH	Data	A O			7	12			•	
[†] PHL	Oata	Any Q	C = 15 = 5 = 000 C		7	12				ns
tpLH	Clock or	4	$C_L = 15 \text{ pF}, R_L = 280 \Omega,$ See Notes 2 and 4		7	14		8	15	
tPHL .	enable	Any Q			12	18		11	17	ns
^t PZH	Output	4.0			8	15		8	15	
^t PZL	Control	Any Q			11	18		11	18	ns
tPHZ	Output		C _L = 5 pF, R _L = 280 Ω,		6	9		5	9	
IPLZ	Control	Any Q	See Note 3		8	12		7	12	hs

NOTES: 2. Maximum clock frequency is tested with all outputs loaded.

4. Load circuits and voltage waveforms are shown in Section 1.

f_{max} = maximum clock frequency

tpLH = propagation delay time, low-to-high-level output

TPHL ≡ propagation delay time, high-to-low-level output

tpZH = output enable time to high level tpzL = output enable time to low level

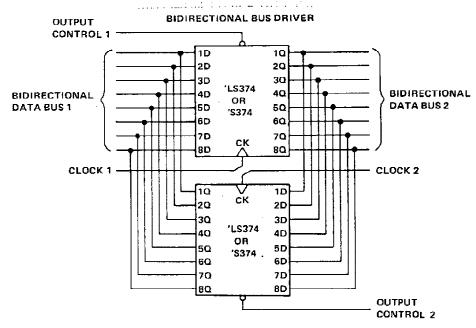
 $tpHZ \equiv output disable time from high level$

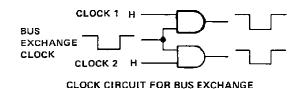
tpLz = output disable time from low level

 $^{^{\}ddagger}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_{A} = 25 ^{\circ}\text{C}$.

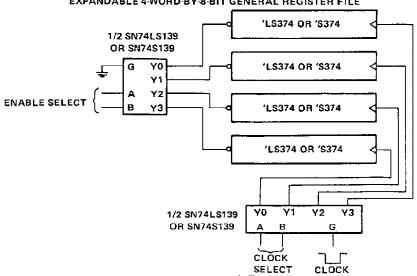
Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.

TYPICAL APPLICATION DATA





EXPANDABLE 4-WORD BY-8-BIT GENERAL REGISTER FILE





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description (continued)

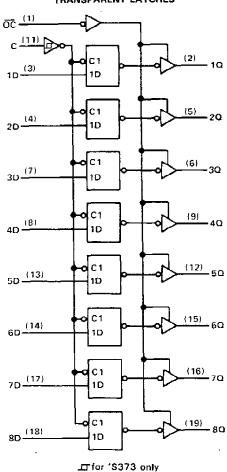
The eight flip-flops of the 'LS374 and 'S374 are edge-triggered D-type flip-flops. On the positive transition of the clock, the Q outputs will be set to the logic states that were setup at the D inputs.

Schmitt-trigger buffered inputs at the enable/clock lines of the 'S373 and 'S374 devices, simplify system design as ac and do noise rejection is improved by typically 400 mV due to the input hysteresis. A buffered output control input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state the outputs neither load nor drive the bus lines significantly.

The output control does not affect the internal operation of the latches or flip-flops. That is, the old data can be retained or new data can be entered even while the outputs are off.

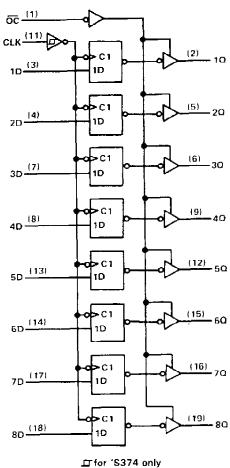
logic diagrams (positive logic)

'LS373, 'S373 TRANSPARENT LATCHES



Pin numbers shown are for DW, J, N, and W packages.

'LS374, 'S374 POSITIVE-EDGE-TRIGGERED FLIP-FLOPS



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